

## Optical Properties of $(As_2S_3)_{100-x}(Sb_2S_3)_x$ Amorphous Films with Small Content of Antimony

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Present report is devoted to investigation of influence of laser illumination on transmission spectra and optical parameters of  $(As_2S_3)_{100-x}(Sb_2S_3)_x$  ( $x=2, 4, 10$  and 15 mol.%) amorphous films.

Thin films were obtained by vacuum evaporation of the glasses of corresponding compositions from quasiclosed effusion cells onto cold (293 K) silica substrates. The films thickness was  $\sim 1 \mu\text{m}$ . Uniform thickness of layers was provided by planetary rotation of substrates. Unfocused illumination of semiconductor laser ( $\lambda=530 \text{ nm}$ ,  $P=100 \text{ mW}$ ) was used for exposure of films. Investigation of transmission spectra of films was carried out by means of "МДР-23" spectrometer in the wavelength region of 450 - 800 nm at  $T=300 \text{ K}$ .

The investigations have shown that with growing of Sb content (from 0.8 to 6 at.%) in the composition of films, transmission spectra are shifted into longwave region testifying to decrease of pseudoforbidden gap width ( $E_g$ ) of films. Refractive index ( $n$ ) in this case is growing (Table).

x, mol.%	Parameter	Exposure, min			
		0	1	3	5
2	$E_g$ , eV	2.354	2.298	2.292	2.287
	n	2.275	2.323	2.332	2.340
4	$E_g$ , eV	2.349	2.309	2.305	2.297
	n	2.284	2.316	2.320	2.326
10	$E_g$ , eV	2.342	2.264	2.262	2.260
	n	2.366	2.430	2.442	2.448
15	$E_g$ , eV	2.334	2.276	2.270	2.267
	n	2.442	2.496	2.508	2.514

With the illumination time growing absorption edge of films is shifting into longwave region.  $E_g$  of films under illumination is decreasing and  $n$  is growing. Here, maximum edge shift under equal expositions conditions is observed for films with antimony content 4 at.%.

The obtained results are discussed from the point of view of films structure and photostructural transformations in them.